

MS/RF PCM/PROCESS CHECKLIST SUB-WORKING GROUP MINUTES

Date: October 21, 2009

Location: Teleconference

Time: 10:00am (Pacific)

Participants:

Chelsea Boone – GSA
David Schwan – RF Micro Devices (RFMD)
Steffen Richter – X-FAB
Aniruddha Joshi – Skyworks Solutions
Philippe Jansen – IMEC
Ehrenfried Seebacher – austriamicrosystems AG
Larry Mehringer – Total Quality Consulting
Jay Seaton – Evolutionary Operations Consulting
Paul Hurwitz – Jazz Semiconductor

Meeting Purpose:

Now that we have identified a standard list of parameters that one would measure for a device for the PCM Checklist, we need to identify which methodologies are used. Foundries have different ways of saying what the result is. We want to make sure the values of the parameters are meaningful to the fabless customer.

End Result/Conclusions:

- Per the working group's feedback, more changes were made to the PCM parameter list. To view the changes made, please see Version 3 of the PCM parameter list.
- Next Meeting: Now that the parameter list is complete, we now need to look at how people would expect these parameters to be measured. The Working Group can help to standardize the measurement algorithms. The foundries can provide the next level of data if needed by the company, as this usually means a more serious problem is occurring. Before our next meeting, working group participants will select a parameter description in column B and provide a neutral definition (how they expect the parameter to be measured).
Measurements methodology and terminology standardization meeting -
November 18, 2009, 10:00am (Pacific)